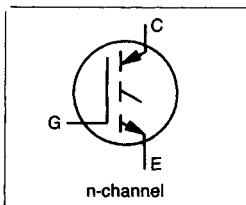


### INSULATED GATE BIPOLAR TRANSISTOR

Fast Speed IGBT



### Description

Insulated Gate Bipolar Transistors (IGBTs) from International Rectifier have higher current densities than comparable bipolar transistors, while at the same time having simpler gate-drive requirements of the familiar power MOSFET. They provide substantial benefits to a host of higher-voltage, higher-current applications.

The performance of various IGBTs varies greatly with frequency. Note that IR now provides the designer with a speed benchmark ( $f_{IC2}$ , or the "half-current frequency"), as well as an indication of the current handling capability of the device. Refer to Figure 14.

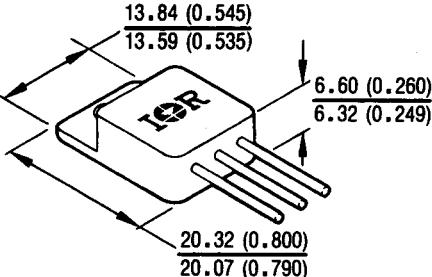
### Product Summary

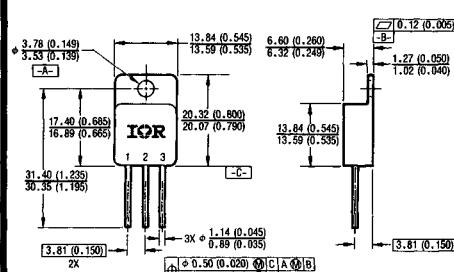
Part Number	$V_{(BR)CES}$	$V_{CE(on)}$	$I_C$	$E_{ts}$
IRGMC30F	600V	2.1V	23A	3.5 mJ

### Features:

- Electronically Isolated and Hermetically Sealed
- Simple Drive Requirements
- Latch-proof
- Fast Speed operation 3 kHz ~ 8 kHz
- Switching-Loss Rating includes all "tail" losses
- Ceramic Eyelets

### CASE STYLE AND DIMENSIONS


**CAUTION**

 BERYLLIA WARNING PER MIL-S-1950B  
SEE PAGE G-65


NOTES:  
 1. DIMENSIONING & TOLERANCING PER ANSI Y14.5M - 1982.  
 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).

LEGEND  
 1. COLLECTOR  
 2. Emitter  
 3. GATE

\*For leadform configuration see page G-65, fig. 15

Conforms to JEDEC Outline TO-254AA\*  
Dimensions in Millimeters and (Inches)

**Absolute Maximum Ratings**

	Parameter	Max.	Units
$I_C @ T_C = 25^\circ\text{C}$	Continuous Collector Current	23	A
$I_C @ T_C = 100^\circ\text{C}$	Continuous Collector Current	12	
$I_{CM}$	Pulsed Collector Current ①	92	
$V_{CE}$	Collector-to-Emitter Breakdown Voltage	600	V
$V_{GE}$	Gate-to-Emitter Voltage	$\pm 20$	
$I_{LM}$	Clamped Inductive Load Current ②	92	A
$P_D @ T_C = 25^\circ\text{C}$	Maximum Power Dissipation	75	W
$P_D @ T_C = 100^\circ\text{C}$	Maximum Power Dissipation	30	
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
	Lead Temperature, for 10 sec.	300 (0.063 in. (1.6mm) from case)	
	Weight	9.3 (typical)	g

**Thermal Resistance**

	Parameter	Min.	Typ.	Max.	Units
$R_{AJC}$	Junction-to-Case	—	—	1.67	K/W ⑥
$R_{FCS}$	Case-to-Sink, flat, greased surface	—	0.21	—	
$R_{AJA}$	Junction-to-Ambient, typical socket mount	—	—	48	

**Electrical Characteristic @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$V_{(BR)CES}$	Collector-to-Emitter Breakdown Voltage	600	—	—	V	$V_{GE} = 0\text{V}, I_C = 1.0\text{ mA}$
$V_{(BR)ECS}$	Emitter-to-Collector Breakdown Volt. ④	24	—	—		$V_{GE} = 0\text{V}, I_C = 1.0\text{ A}$
$\Delta V_{(BR)CES}/\Delta T_J$	Temp. Coeff. of Breakdown Voltage	—	0.69	—	V/ $^\circ\text{C}$	$V_{GE} = 0\text{V}, I_C = 1.0\text{ mA}$
$V_{CE(on)}$	Collector-to-Emitter Saturation Voltage	—	—	2.1	V	$V_{GE} = 15\text{V}, I_C = 12\text{A}$ See Fig. 4
		—	—	2.4		$V_{GE} = 15\text{V}, I_C = 23\text{A}$
		—	—	2.2		$V_{CE} = 15\text{V}, I_C = 12\text{A}, T_J = 125^\circ\text{C}$
		3.0	—	5.5		$V_{CE} = V_{GE}, I_C = 250\text{ }\mu\text{A}$
$V_{GE(th)}$	Gate Threshold Voltage	—	—	—	mV/ $^\circ\text{C}$	$V_{CE} = V_{GE}, I_C = 250\text{ }\mu\text{A}$
$\Delta V_{GE(th)}/\Delta T_J$	Temp. Coeff. of Threshold Voltage	—	-11	—		
$g_{fe}$	Forward Transconductance ⑤	6.1	—	—	S	$V_{CE} = 15\text{V}, I_C = 12\text{A}$
$I_{CES}$	Zero Gate Voltage Collector Current	—	—	50	$\mu\text{A}$	$V_{GE} = 0\text{V}, V_{CE} = 480\text{V}, T_J = 25^\circ\text{C}$
		—	—	1000		$V_{GE} = 0\text{V}, V_{CE} = 480\text{V}, T_J = 125^\circ\text{C}$
$I_{GES}$	Gate-to-Emitter Leakage Current	—	—	$\pm 100$	nA	$V_{GE} = \pm 20\text{V}$

**Notes:**

- ① Repetitive rating;  $V_{GE} = 20\text{V}$ , pulse width limited by max. junction temperature (See figure 12b).
- ②  $V_{CC} = 80\%$  ( $BV_{CES}$ ),  $V_{GE} = 20\text{V}$ ,  $L \geq 10\text{ }\mu\text{H}$ ,  $R_G = 10\Omega$ , (See figure 12a)

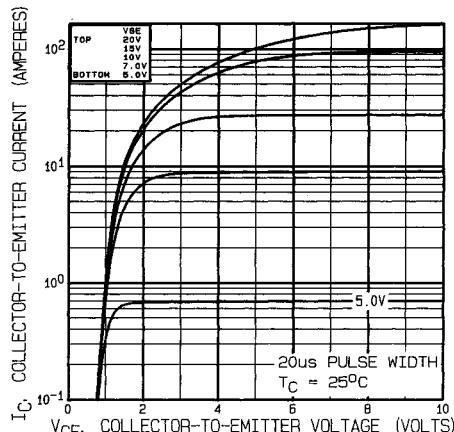
③ Pulse width  $\leq 80\text{ }\mu\text{s}$ ; duty factor  $\leq 0.1\%$ .

④ Pulse width  $\leq 5\text{ }\mu\text{s}$ , single shot

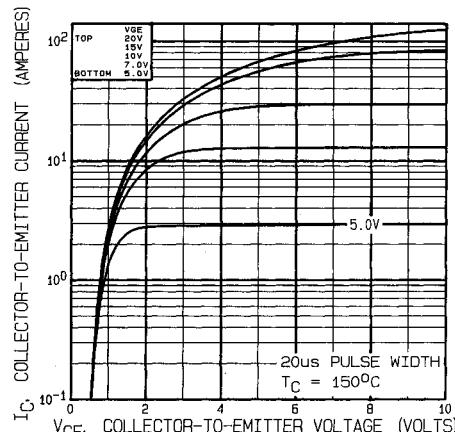
⑤ K/W equivalent to  $^\circ\text{C}/\text{W}$

**Switching Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$Q_G$	Total Gate Charge (turn-on)	—	27	54	nC	$I_C = 12\text{A}$ , $V_{CC} = 300\text{V}$ See Figure 6. $V_{GE} = 15\text{V}$
$Q_{GE}$	Gate - Emitter Charge (turn-on)	—	4	8		
$Q_{GC}$	Gate - Collector Charge (turn-on)	—	12	24		
$t_{d(on)}$	Turn-On Delay Time	—	—	50	ns	See test circuit, figure 13. $I_C = 12\text{A}$ , $V_{CC} = 480\text{V}$ $T_J = 25^\circ\text{C}$
$t_r$	Rise Time	—	—	42		
$t_{d(off)}$	Turn-Off Delay Time	—	—	320		
$t_f$	Fall Time	—	—	500	mJ	$V_{GE} = 15\text{V}$ , $R_G = 7.5\Omega$ Energy losses include "tail". Also see figures 9, 10, & 11.
$E_{on}$	Turn-On Switching Loss	—	0.40	—		
$E_{off}$	Turn-Off Switching Loss	—	2.1	—		
$E_{ts}$	Total Switching Loss	—	2.5	3.5	mJ	
$t_{d(on)}$	Turn-On Delay Time	—	25	—		$I_C = 12\text{A}$ , $V_{CC} = 480\text{V}$
$t_r$	Rise Time	—	21	—		$T_J = 125^\circ\text{C}$
$t_{d(off)}$	Turn-Off Delay Time	—	290	—		$V_{GE} = 15\text{V}$ $R_G = 7.5\Omega$
$t_f$	Fall Time	—	590	—	mJ	
$E_{ts}$	Total Switching Loss	—	4.0	—		
$L_E$	Internal Emitter Inductance	—	8.7	—		nH Measured 5mm from package.
$C_{ies}$	Input Capacitance	—	670	—	pF	$V_{GE} = 0\text{V}$
$C_{ces}$	Output Capacitance	—	100	—		$V_{CC} = 30\text{V}$
$C_{res}$	Reverse Transfer Capacitance	—	10	—		See fig 5. $f = 1.0 \text{ MHz}$
$C_{cc}$	Collector-to-Case Capacitance	—	12	—		



**Fig. 1 — Typical Output Characteristics,  
 $T_C = 25^\circ\text{C}$**



**Fig. 2 — Typical Output Characteristics,  
 $T_C = 150^\circ\text{C}$**

# IRGMC30F

ICR

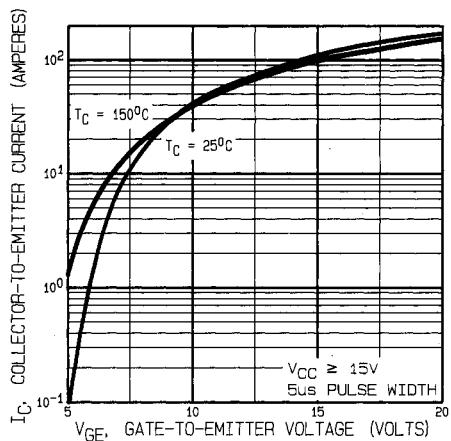


Fig. 3 — Typical Transfer Characteristics

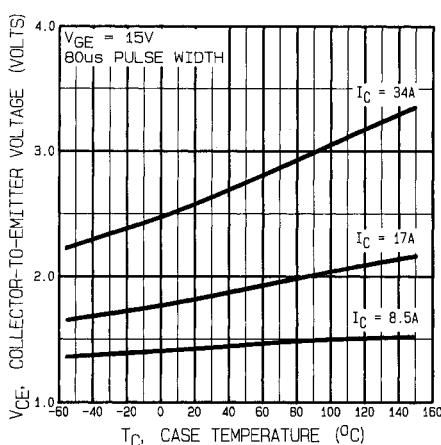


Fig. 4 — Collector-to-Emitter Saturation Voltage vs. Case Temperature

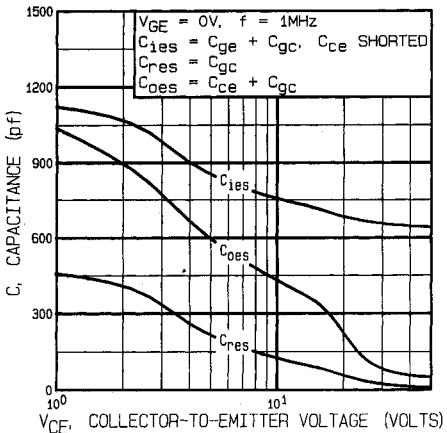


Fig. 5 — Typical Capacitance vs. Collector-to-Emitter Voltage

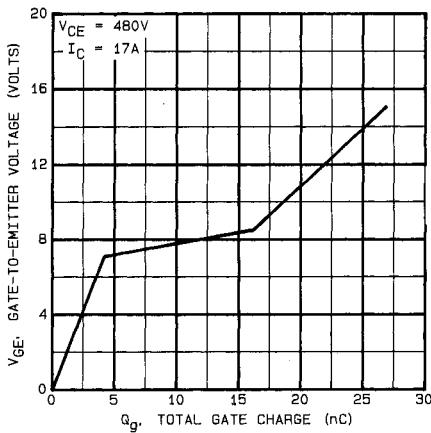
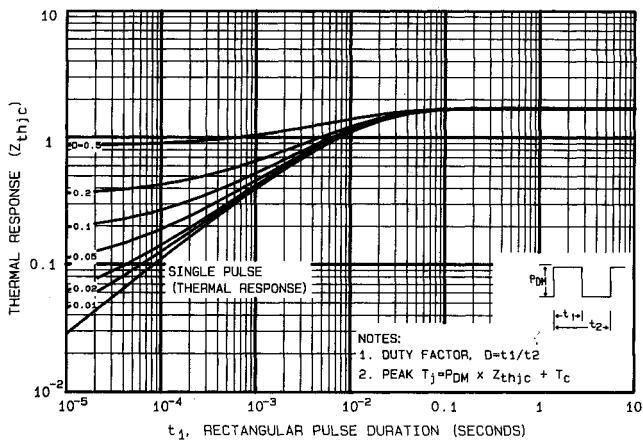
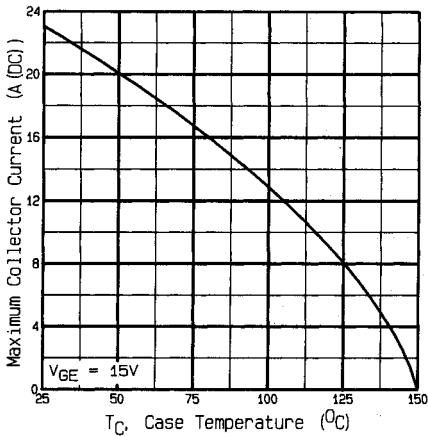


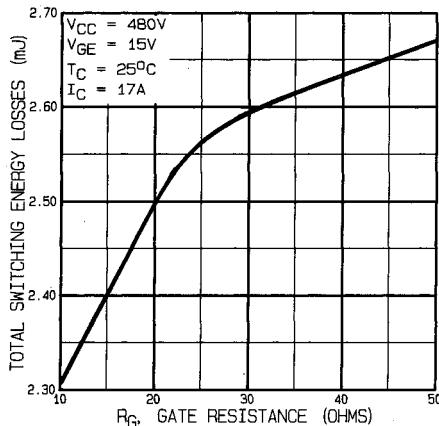
Fig. 6 — Typical Gate Charge vs. Gate-to-Emitter Voltage



**Fig. 7 — Maximum Effective Transient Thermal Impedance, Junction-to-Case**



**Fig. 8 — Maximum Collector Current vs. Case Temperature**



**Fig. 9 — Typical Switching Losses vs. Gate Resistance**

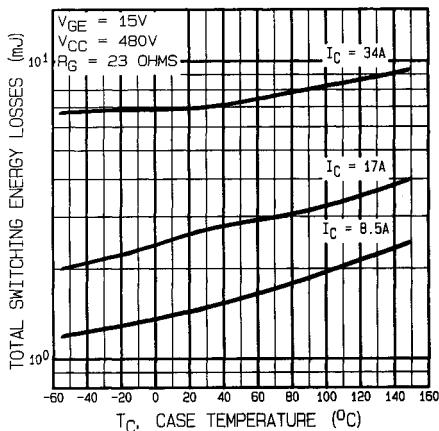


Fig. 10 — Typical Switching Losses vs. Case Temperature

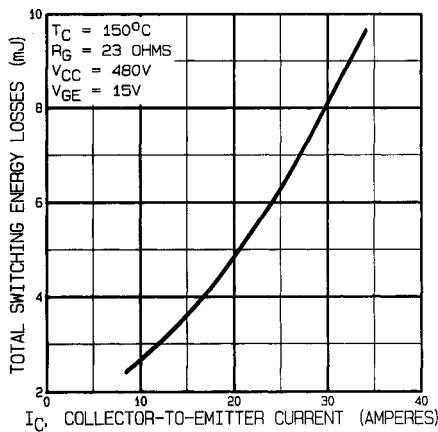


Fig. 11 — Typical Switching Losses vs. Collector-to-Emitter Current

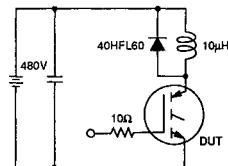


Fig 12a. Clamped Inductive Load Test Circuit

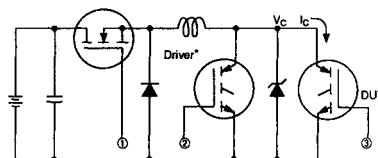


Fig 13a. Switching Loss Test Circuit

• Driver same type as DUT,  $V_C = 480\text{V}$

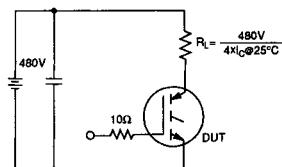


Fig 12b. Pulsed Collector Current Test Circuit

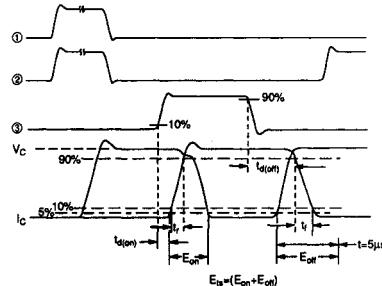


Fig 13b. Switching Loss Waveforms

For both, power dissipation = 19W

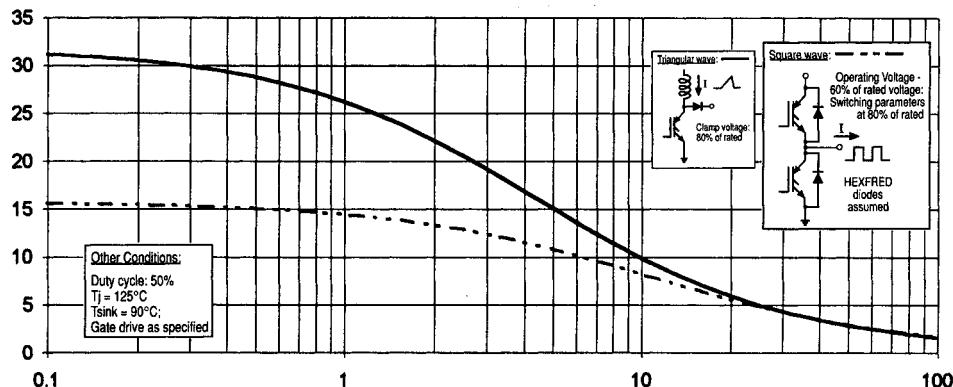


Fig. 14 — Typical Load Current vs. Frequency  
(For square wave,  $I = I_{\text{RMS}}$  of fundamental; for triangular wave,  $I = I_{\text{PK}}$ )

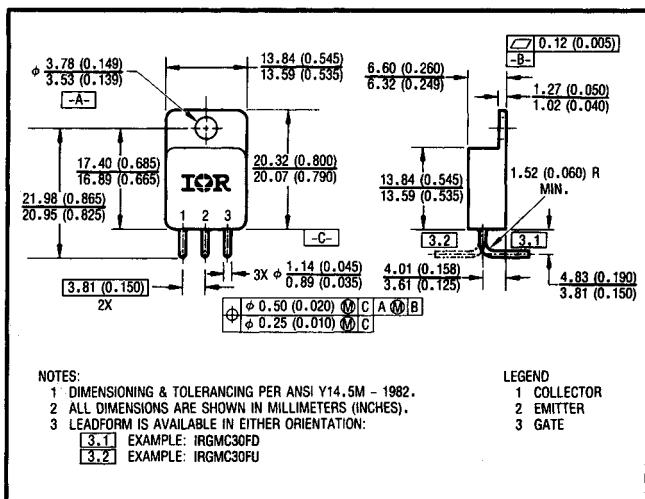


Fig. 15 — Optional Leadforms for Outline TO-254